

**Search Notes**

Application/Control No.

10/669,621

Examiner

Randall Chin

Applicant(s)/Patent under  
Reexamination

WONG ET AL.

Art Unit

1744

**SEARCHED**

Class	Subclass	Date	Examiner
15	21.1		
15	77		
15	97.1	✓	
15	102	7/21/2005	RC

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor name search	7/21/2005	RC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner